CSU Short Course
X-ray Diffraction and Scattering Methods for Materials Analysis

This 2-day workshop will introduce you to different X-ray diffraction, X-ray and light scattering methods for characterization of soft and hard materials. Focus will be on demonstrations and data processing and interpretation.

- **Day 1**: XRD for structural analysis
- **Day 2**: SAXS and DLS for particle size distribution and molecular weight estimations

Take advantage of a unique opportunity to have samples analyzed for more advanced analysis prior to the workshop.

**Featured Speakers**
- Dr. Travis Bailey - CSU
- Dr. Davor Balzar - University of Denver
- Dr. Benjamin Krueger - Bruker
- Dr. Matt McGann - Malvern Instruments

**When:** Sep 14-15, 2017

**Where:** Colorado State University
Fort Collins, CO 80523

**Cost:**
- CSU participants: $100/day
- External: $500/day

**Registration:**
cif.colostate.edu/cif-short-course-2017

Open to students, researchers and professionals in the field. Basic knowledge of X-ray diffraction is expected.

**Questions:** Erin.Stuckert@colostate.edu